

SW Test Workshop

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An Innovative Design and Implementation of Vertical Probe Card for High Speed Loopback(12Gbps) Application



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- Background
- Introduction
- Electrical Performance
- Design of Taguchi Methods
- Experiment Validation
- Conclusion

There are several types of high-speed transmission interface which are shown at chart below. In order to achieve the required speed on the wafer level testing, the demand of the advanced loopback design is certainly more and more important.



How to improve the performance of the probe card There are several factors, such as

- 1. PCB
- 2. SUB.
- 3. Needles







■ The channel1. of P/C measurement result and eye diagram

Channel 1.



Channel 1. 6Gbps



Channel 1. 2Gbps







Introduction



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Introduction

■ About Super Eye TM technology

MPI design the impedance matching on the transmission line.



Super Eye[™] technology is patented and patents pending.

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Electrical Performance (Sim.)

■ By using 3D EM software and Super Eye TM technology, it will help to progress the conventional electrical performance.





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Electrical Performance

Measurement result of P/C
The simulation and measurement results are inconsistent.





Electrical Performance

There are several sensitive factors which cause the inconsistency between the measurement result and simulation. MPI analyzed those factors and made an improvement to the simulation resulting in more accurate results.



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We found 4 sensitive factors during the process of sensitivity analysis.





We found 4 sensitive factors during the process of sensitivity analysis.





Each sensitive factor might impact different Via, Metal, or landing pad.



Taguchi Methods : Orthogonal Arrays & Experimental Data log, S/N Ratios.

Experiment	Α	В	С	D	S/N Ratios	7
1	1	1	1	1		
2	1	2	2	2		V.
3	1	3	3	3		AB
4	2	1	2	3		AI
5	2	2	3	1		-
6	2	3	1	2		
7	3	1	3	2		
8	3	2	1	3		
9	3	3	2	1		



Analysis Result

According to the sensitive factors, we use Taguchi Methods to improve the design and let the performance better.



Measurement system



Measurement system
We adopted SOLT calibration method and de-embedded each probe to generate measurement result.



Measurement result

The measurement result shows the characteristics are improved.



Eye diagram of 5 Gbps

1.2-1.0-0.8-Eye_trace 0.6 0.4 0.2 0.0 -0.2-50 100 150 200 250 300 350 400 time, psec

Super Eye [™] 5Gbps

Rise/Fall time = 50 ps Data rate = 5 Gbps Data type = PRBS(2³²-1) Vo/Vi *100% = 74%

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Eye diagram of 6 Gbps

1.2 1.0 0.8 Eye_trace 0.6 0.4 0.2 0.0 -0.2-50 100 150 200 250 300 time, psec

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Super Eye [™] 66bps

Rise/Fall time = 41.667 ps Data rate = 6 Gbps Data type = PRBS(2³²-1) Vo/Vi *100% = 72%

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Conventional P/C 6Gbps

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Eye diagram of 8 Gbps

1.2-1.0 0.8 Eye_trace 0.6 0.4 0.2 0.0 -0.2 240 20 40 60 160 180 200 220 80 100 120 140 time, psec

Super Eye [™] 8Gbps

Rise/Fall time = 31.25 ps Data rate = 8 Gbps Data type = PRBS(2³²-1) Vo/Vi *100% = 66%

Eye diagram of 10 Gbps



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Super Eye [™] 10Gbps

Rise/Fall time = 25 ps Data rate = 10 Gbps Data type = PRBS(2³²-1) Vo/Vi *100% = 64%





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Eye diagram of 12 Gbps



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Super Eye [™] 12Gbps

Rise/Fall time = 20.8 ps Data rate = 12 Gbps Data type = PRBS(2³²-1) Vo/Vi *100% = 60%





Conclusion

Super Eye [™] technology

 Super Eye [™] technology can support 12Gbps for vertical probe card loopback application on high speed transmission interface (USB3.0: 5Gbps, SATA3: 6Gbps, PCI-E 3.0: 8Gbps, Ethernet: 10Gbps...etc.).

2. Improve conventional loopback design: Impendence matching on the transmission line to improve electrical performance.

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Thank you 5TH ANNIVERSAR 2 - 0 - 1 - 5

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